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375	2.29 219 346	2/25/64	sh
367 381	135 93 314	: 1	
455 708	5'70 313 321 420	,	zh
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375 370	222 286 289	8/39/04	ch
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)

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IEEE	2/25/04	Eh
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Search Notes (continued)

Application/Control No.

Applicant(s)/Patent under Reexamination
ERIKSSON, ANDERS

09/655,755 Examiner

Art Unit 2637

Edith M. Chang

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84	621-625	5/16/05	ek
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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